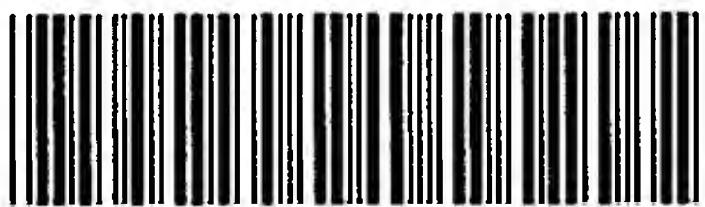


Search Notes



Application/Control No.

10/806.045

Examiner

Phuong Huynh

**Applicant(s)/Patent under
Reexamination**

KOURI ET AL.

Art Unit

2857

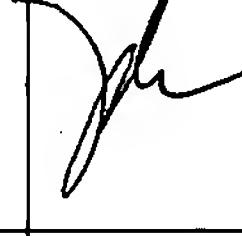
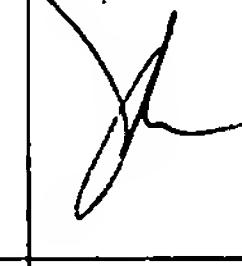
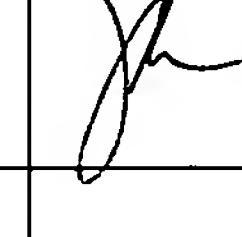
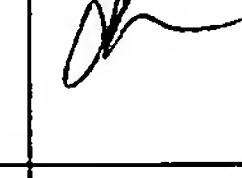
SEARCHED

INTERFERENCE SEARCHED

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
356/32,34,300,303,450,451,432,445,4 48,213,228,947,253,254,255,226,340, 239,237,222 with text Lippmann- Schwinger	8/5/2005	
Consulted with Michael Nghiem for search area as well as double pattening checking	8/2/2005	
Consulted with Marc Hoff for searching area: Optics	8/4/2005	
Talked with Sang Nguyen for optics search strategy	8/4/2005	
Google and IEEE searching (text: Lippmann-Schwinger equation solution; Inverse scattering solution; approximation method;	8/1/2005	
Google and IEEE searching (text: iterative solution, inverse scattering problems	8/1/2005	